2-Propanol CMOS

(iso-propyl alcohol)





Material No.: 9079-05 Batch No.: 0000135184 Manufactured Date: 2016/01/11

Retest Date: 2021/01/09

Certificate of Analysis

| Test | Specification | Result |
|------------------------------------|---------------|--------|
| Assay (CH3CHOHCH3) | >= 99.5 % | 100.0 |
| Color (APHA) | <= 10 | 5 |
| Residue after Evaporation | <= 4 ppm | 1 |
| Solubility in H₂O | Passes Test | PT |
| Nater (H₂O)(by Karl Fischer titrn) | <= 0.05 % | 0.01 |
| Acidity (µeq/g) | <= 0.2 | 0.1 |
| Alkalinity (µeq/g) | <= 0.1 | < 0.1 |
| Chloride (CI) | <= 0.1 ppm | < 0.1 |
| Phosphate (PO4) | <= 0.3 ppm | < 0.3 |
| Trace Impurities - Aluminum (Al) | <= 50.0 ppb | < 5.0 |
| Arsenic and Antimony (as As) | <= 10 ppb | < 10 |
| Frace Impurities – Barium (Ba) | <= 20.0 ppb | < 1.0 |
| Frace Impurities - Beryllium (Be) | <= 100.0 ppb | < 1.0 |
| Frace Impurities – Bismuth (Bi) | <= 100.0 ppb | < 10.0 |
| Гrace Impurities – Boron (В) | <= 10.0 ppb | < 5.0 |
| Frace Impurities - Cadmium (Cd) | <= 20.0 ppb | < 1.0 |
| Frace Impurities - Calcium (Ca) | <= 50.0 ppb | 1.8 |
| Frace Impurities - Chromium (Cr) | <= 20.0 ppb | < 1.0 |
| Frace Impurities - Cobalt (Co) | <= 20.0 ppb | < 1.0 |
| Frace Impurities – Copper (Cu) | <= 10.0 ppb | < 1.0 |
| Frace Impurities – Gallium (Ga) | <= 50.0 ppb | < 1.0 |
| Frace Impurities - Germanium (Ge) | <= 50.0 ppb | < 10.0 |
| Frace Impurities – Gold (Au) | <= 20.0 ppb | < 5.0 |
| Heavy Metals (as Pb) | <= 200 ppb | < 100 |

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|-------------------------------------|----------------|--------|
| Trace Impurities – Iron (Fe) | <= 50.0 ppb | < 1.0 |
| Trace Impurities – Lead (Pb) | <= 20.0 ppb | < 10.0 |
| Trace Impurities – Lithium (Li) | <= 50.0 ppb | < 1.0 |
| Trace Impurities – Magnesium (Mg) | <= 20.0 ppb | < 1.0 |
| Trace Impurities – Manganese (Mn) | <= 15.0 ppb | < 1.0 |
| Trace Impurities – Molybdenum (Mo) | <= 100.0 ppb | < 5.0 |
| Trace Impurities – Nickel (Ni) | <= 10.0 ppb | < 5.0 |
| Trace Impurities – Niobium (Nb) | <= 100.0 ppb | < 1.0 |
| Trace Impurities – Potassium (K) | <= 100.0 ppb | < 10.0 |
| Trace Impurities – Silicon (Si) | <= 50.0 ppb | < 10.0 |
| Trace Impurities – Silver (Ag) | <= 20.0 ppb | < 1.0 |
| Trace Impurities – Sodium (Na) | <= 100.0 ppb | < 5.0 |
| Trace Impurities – Strontium (Sr) | <= 20.0 ppb | < 1.0 |
| Trace Impurities – Tantalum (Ta) | <= 100.0 ppb | < 5.0 |
| Trace Impurities – Thallium (Tl) | <= 10.0 ppb | < 5.0 |
| Trace Impurities - Tin (Sn) | <= 100.0 ppb | < 10.0 |
| Trace Impurities – Titanium (Ti) | <= 20.0 ppb | < 1.0 |
| Trace Impurities - Vanadium (V) | <= 100.0 ppb | < 1.0 |
| Trace Impurities - Zinc (Zn) | <= 50.0 ppb | < 1.0 |
| Trace Impurities – Zirconium (Zr) | <= 100.0 ppb | < 1.0 |
| Particle Count – 0.2 µm and greater | <= 5000 par/ml | 937 |
| Particle Count – 0.3 µm and greater | <= 5000 par/ml | 127 |
| Particle Count – 0.5 µm and greater | <= 50 par/ml | 9 |
| Particle Count – 1.0 µm and greater | <= 8 par/ml | 2 |

For Microelectronic Use

Country of Origin: US

Packaging Site: Paris Mfg Ctr & DC



Phillipsburg, NJ 9001:2008, 14001:2004, FSSC 22000
Paris, KY 9001:2008
Mexico City, Mexico 9001:2008
Deventer, The Netherlands 9001:2008, 14001:2004, 13485:2003
Gliwice, Poland 9001:2008
Selangor, Malaysia 9001:2008
Dehradun, India, 9001:2008, 14001:2004, 13485:2003
Mumbai, India, 9001:2008, 17025:2005

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